

11-10-1998

U.S. PATENT AND T



100875265

Case Docket No. 980182

U.S. DEPARTMENT OF COMMERCE  
Patent and Trademark Office

**CORRECTIVE RECORDATION FORM COVER SHEET**  
**PATENTS ONLY**

To the Assistant Commissioner for Patents.  
Please record the attached original documents or copy thereof.

1. Name of conveying party(ies):

**Masataka MIZUKOSHI; Hidehiko AKASAKI; Masao NAKANO;  
Yasuhiro FUJII; Shinnosuke KAMATA; Makoto YANAGISAWA;  
Yasurou MATSUZAKI; Toyonobu YAMADA; Masami MATSUOKA;  
Hiroyoshi TOMITA**

Additional name(s) of conveying party(ies) attached? **Yes** No **XX**

2. Name and address of receiving party(ies):

Name: **FUJITSU LIMITED**  
Street Address: 1-1, Kamikodanaka 4-chome  
Nakahara-ku, Kawasaki-shi  
Kanagawa 211-8588 JAPAN

Additional name(s) & address(es) attached? **Yes** No **XX**

3. Nature of conveyance: XX **Other**

***CORRECTIVE ASSIGNMENT IN ORDER TO CORRECT THE ASSIGNORS  
ON REEL/FRAME 9319 / 0733***

Execution Date: **June 9, 1998**

4. Title:

**SEMICONDUCTOR WAFER TESTING METHOD WITH IMPROVED  
PROBE PIN CONTACT**

5. Application number(s) or patent number(s): **09/030,349**

If this document is being filed together with a new application, the execution date of the application is:

A. Patent Application No.(s)      B. Patent No.(s)

Additional numbers attached? **Yes** No **XX**

11/10/1998 DNYEN 00000066 09030349

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40.00 OP

**PATENT**  
**REEL: 9566 FRAME: 0252**

6. Name and address of party to whom correspondence concerning document should be mailed:

Name: Armstrong, Westerman, Hattori,  
McLeland & Naughton  
Suite 1000  
1725 K Street, N.W.  
Washington, D.C. 20006

7. Total number of applications and patents involved: 1

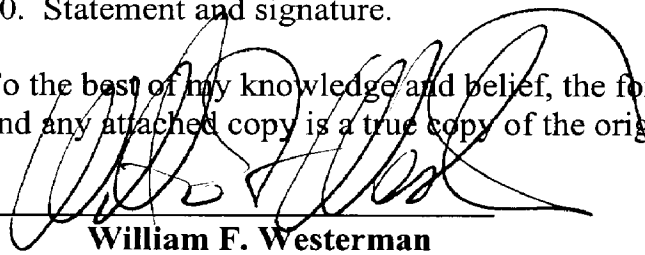
8. Total fee (37 CFR 3.41). . . . . \$ **40.00**

**XX** Check enclosed

9. Deposit Account No.: **01-2340**  
(Two copies of this paper are attached.)

10. Statement and signature.

To the best of my knowledge and belief, the foregoing information is true and correct  
and any attached copy is a true copy of the original document.



**William F. Westerman**  
Reg. No.: **29,988**

Date November 6, 1998

Total number of pages including cover sheet: **4**

WFW/klh

**U.S. ASSIGNMENT**

IN CONSIDERATION of the sum of One Dollar (\$1.00), and of other good and valuable consideration paid to the undersigned inventor(s) (hereinafter ASSIGNOR) by

(Insert ASSIGNEE's  
Name(s) Address(es))

FUJITSU LIMITED, 1-1, Kamikodanaka 4-chome, Nakahara-ku,  
Kawasaki-shi, Kanagawa, 211-8588 Japan

(hereinafter ASSIGNEE), the receipt of which is hereby acknowledged, the undersigned ASSIGNOR hereby sells, assigns and transfers to ASSIGNEE the entire and exclusive right, title and interest to the invention entitled

(Title of Invention)

SEMICONDUCTOR WAFER TESTING METHOD WITH IMPROVED PROBE PIN CONTACT

(\*If the assignment is  
being filed after the filing  
of the application, this  
section must be  
completed)

for which application for Letters Patent of the United States was executed on even date herewith unless otherwise indicated below:

\*filed on February 25, 1998, Serial No. 09/030,349.

(Armstrong, Westerman, Hattori, McLeland & Naughton is hereby authorized to insert the serial code, serial number and/or filing date hereon, when known)

and all Letters Patent of the United States to be obtained therefor on said application or any continuation, divisional, substitute, reissue or reexamination thereof for the full term or terms for which the same may be granted.

The ASSIGNOR agrees to execute all papers necessary in connection with the application and any continuation, divisional, reissue or reexamination applications thereof and also to execute separate assignments in connection with such applications as the ASSIGNEE may deem necessary or expedient.

The ASSIGNOR agrees to execute all papers necessary in connection with any interference, litigation, or other legal proceeding which may be declared concerning this application or any continuation, divisional, reissue or reexamination thereof or Letters Patent or reissue patent issued thereon and to cooperate with the ASSIGNEE in every way possible in obtaining and producing evidence and proceeding with such interference, litigation, or other legal proceeding.

IN WITNESS WHEREOF, the undersigned inventor(s) has (have) affixed his/her/their signature(s).

(Signatures)

<u>Masataka Mizukoshi</u> (SIGNATURE)	<u>Masataka Mizukoshi</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)
<u>Hidehiko Akasaki</u> (SIGNATURE)	<u>Hidehiko Akasaki</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)
<u>Masao Nakano</u> (SIGNATURE)	<u>Masao Nakano</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)
<u>Yasuhiro Fujii</u> (SIGNATURE)	<u>Yasuhiro Fujii</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)
<u>Shinnosuke Kamata</u> (SIGNATURE)	<u>Shinnosuke Kamata</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)
<u>Makoto Yanagisawa</u> (SIGNATURE)	<u>Makoto Yanagisawa</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)
<u>Yasurou Matsuzaki</u> (SIGNATURE)	<u>Yasurou Matsuzaki</u> (TYPE NAME)	<u>June 9, 1998</u> (DATE)

NO LEGALIZATION REQUIRED

*Toyonobu Yamada*

(SIGNATURE)

~~XXXXXXXXXXXX~~

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(DATE)

*Masumi Matsuda*

(SIGNATURE)

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June 9, 1998

(DATE)

*Hiroshi Terada*

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June 9, 1998

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